

Notice of References Cited	Application/Control No. 10/717,823		Applicant(s)/Patent Under Reexamination KRIETEMEYER ET AL.	
	Examiner Jack W. Szeto		Art Unit 2113	Page 1 of 3

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-5,415,053 A	05-1995	Elias, Leonard W.	73/865.7
*	B	US-5,492,022 A	02-1996	Elias, Leonard W.	73/865.7
*	C	US-5,539,652 A	07-1996	Tegethoff, Mauro V.	703/14
*	D	US-5,532,927 A	07-1996	Pink et al.	701/34
*	E	US-5,566,092 A	10-1996	Wang et al.	702/185
*	F	US-5,729,452 A	03-1998	Smith et al.	701/29
*	G	US-6,146,523 A	11-2000	Kenley et al.	210/143
*	H	US-6,338,152 B1	01-2002	Fera et al.	714/48
*	I	US-2002/0077778 A1	06-2002	Cobble et al.	702/183
*	J	US-2003/0208712 A1	11-2003	Louden et al.	714/742
*	K	US-2004/0250191 A1	12-2004	Leaming, Taylor J.	714/742
*	L	US-6,973,396 B1	12-2005	Shah et al.	702/81
*	M	US-7,047,442 B2	05-2006	Sutton, Christopher K	714/25

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	STSARCES, "Final Report: Safety-Related Complex Electronic Systems", Feb. 29, 2000, pp 1-37
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

Notice of References Cited	Application/Control No. 10/717,823		Applicant(s)/Patent Under Reexamination KRIETEMEYER ET AL.	
	Examiner Jack W. Szeto		Art Unit 2113	Page 2 of 3

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-4,999,837 A	03-1991	Reynolds et al.	714/703
*	B	US-5,600,789 A	02-1997	Parker et al.	714/38
*	C	US-5,602,761 A	02-1997	Spoerre et al.	702/179
*	D	US-5,715,178 A	02-1998	Scarola et al.	702/116
*	E	US-6,035,293 A	03-2000	Lantz et al.	707/1
*	F	US-6,041,287 A	03-2000	Dister et al.	702/182
*	G	US-6,077,051 A	06-2000	Centers et al.	417/280
*	H	US-6,397,111 B1	05-2002	Niwa, Tomomitsu	700/11
*	I	US-2002/0170000 A1	11-2002	Gorodetsky et al.	714/30
*	J	US-2002/0166082 A1	11-2002	Ramadei et al.	714/37
*	K	US-6,539,313 B1	03-2003	Bornemann et al.	702/33
*	L	US-2005/0262457 A1	11-2005	Granier et al.	716/004
*	M	US-2005/0268170 A1	12-2005	Kearney et al.	714/032

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

Notice of References Cited	Application/Control No. 10/717,823	Applicant(s)/Patent Under Reexamination KRIETEMEYER ET AL.	
	Examiner Jack W. Szeto	Art Unit 2113	Page 3 of 3

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-5,984,503 A	11-1999	Strickland et al.	700/95
*	B	US-6,243,835 B1	06-2001	Enokido et al.	714/38
*	C	US-6,246,787 B1	06-2001	Hennessey et al.	382/141
*	D	US-5,247,664	09-1993	Thompson et al.	707/10
*	E	US-2004/0064253	04-2004	Brayton et al.	702/002
*	F	US-6,397,111	05-2002	Niwa, Tomomitsu	700/11
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.